·般積層セラミックコンデンサ

(高誘電率系・Class 2)

STANDARD MULTILAYER CERAMIC CAPACITORS (CLASS2: HIGH DIELECTRIC CONSTANT TYPE)

	Code	Temp.characteristics	Operating temp. range
	BJ	В	-25~+85°C
	DJ	X5R*	-55~+85°C
OPERATING TEMP.	B7	X7R	-55~+125°C
		F	-25~+85°C
	F	Y5V	-30~+85°C



^{*}個別仕様の取交しにより、X7R/X7S 仕様に対応している場合があります。

FEATURES

- ・実装密度の向上が図れます
- ・モノリシックの構造のため、信頼性が高い
- ・同一形状、静電容量範囲が広い

- · Improve Higher Mounting Densities.
- · Multilayer block structure provides higher reliability
- · A wide range of capacitance values available in standard case sizes.

APPLICATIONS

- ·一般電子機器用
- ・通信機器用(携帯電話、PHS、コードレス電話 etc.)

- · General electronic equipment
- · Communication equipment (cellular phone, PHS, other wireless applications, etc.)

形名表記法 **ORDERING CODE**

U										
定格電	注〔VDC〕									
Α	4									
J	6.3									
L	10									
Е	16									
T	25									
G	35									
U	50									

シリーズ名 積層コンデンサ М

3 端子電極 メッキ品 形状寸法 (EIA)L×W[mm] 042(01005) 0.4×0.2 063(0201) 0.6×0.3 105(0402) 1.0×0.5

温度特性 BJ X5R B7 X7R $\triangle F$ Y5V

6 公称静電容量〔pF〕 例 1000 102 223 22000

容量許容差 ± 10% М ±20% +80 % -20 % Z

8 製品厚み (mm) 0.2 0.3 V 0.5 9 個別仕様 標準

1 包装 φ178mm テーピング . (2mmピッチ)



Rated voltage(VDC)

6.3 16 25 G 35 IJ 50

Series name Multilayer ceramic M capacitor

End termination

△=スペース

Dimensions (case size) (L×W) [mm] 042(01005) 0.4×0.2 063(0201) 0.6×0.3

5 Temperature characteristics code

В BJ В7 X7R △F Y5V △=Blank space

Nominal capacitance (pF) example 1000 102

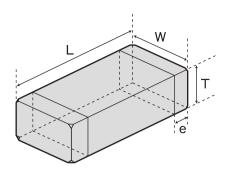
Capacitance tolerance ± 10% М ± 20% +80 % -20 % Ζ

8 Thickness (mm) 0.2 0.3 0.5 9 Special code Standard products

10 Packaging φ 178mm Taping (2mm pitch)

Internal code Standard Products △=Blank space

^{*}We may provide X7R/X7S for some items according to the individual specification.



Type (EIA)	L	W	Т		е
☐MK042	0.4±0.02	0.2 ± 0.02	0.2±0.02	С	0.1±0.03
(01005)	(0.016±0.001)	(0.008 ± 0.001)	(0.008±0.001)	C	(0.004±0.001)
☐MK063	0.6±0.03	0.3 ± 0.03	0.3±0.03	Р	0.15±0.05
(0201)	(0.024±0.001)	(0.012 ± 0.001)	(0.012±0.001)	Р	(0.006±0.002)
☐MK105	1.0±0.05*1	0.5±0.05*1	0.5±0.05*1	1/	0.25±0.10
(0402)	(0.039 ± 0.002)	(0.020 ± 0.002)	(0.020±0.002)	V	(0.010±0.004)
					Unit: mm (inch)

注: *1 ±0.1mm 公差あり

Note: *1. Inclulding dimension tolerance \pm 0.1mm

概略バリエーション AVAILABLE CAPACITANCE RANGE

■汎用積層セラミックコンデンサ (General Multilayer Ceramic capacitors)

	Туре	0	142			0	63											105								
	Temp.char.	B/	X5R	I	B/X5R			X5R			B/X7F	3			B/>	(5R				X5R				F/Y5V	'	
Cap	VDC																									
[pF]	[pF:3digits]	100	6.3V	25V	16V	10V	10V	6.3V	4V	50V	25V	16V	50V	35V	25V	16V	10V	6.3V	10V	6.3V	4V	50V	25V	16V	10V	6.3\
100	101																									
150	151																									
220	221																									
330	331	С		Р																						
470	471																									
680	681																									
1000	102																									
1500	152									V			V													
2200	222				Р																					
3300	332																									
4700	472																									
6800	682					Р																				
10000	103																					V				
15000	153										V															
22000	223					Р						1/			V								V			
33000	333											V														
47000	473						Р	Р																٧		
68000	683															V										
100000	104						Р	Р				V		V	V		W							٧		
220000	224																V	V							V	
330000	334								Р																	
470000	474																		V							
1000000	105																		V	V						V
2200000	225																									
3300000	335																				V					
4700000	475																				V					

注:グラフの記号は製品厚み記号です。Note: Letters in the table indicate thickness.

温度特性コード Temp.char.Code		Tem	温度特性 perature characteri	stics		静電容量許容差〔%〕	tanδ(%)	
	+1/2	規格 e standard	温度範囲(℃) Temperature range	基準温度(℃) Ref. Temp.	静電容量変化率〔%〕 Capacitance change	Capacitance tolerance	Dissipation factor	
B/BJ	JIS	JIS B		20	±10	-10(14)		
D/DJ	EIA	X5R	-55~+85	25	±15	±10(K) ±20(M)	2.5 max.*	
B7	EIA	X7R	−55~+125	25	±15	<u></u> 20(W)		
г	JIS	F	-25~+85	20	+30/-80	+80 -20	7.0 max.*	
г	EIA	Y5V	−30~+85	25	+22/-82	-20 ⁽²⁾	7.0 max.	

- *: 代表的な値を記載しています。詳細はアイテム一覧を参照ください。
- *: The figure indicate typical value. Please refer to PART NUMBERS table.













アイテム一覧 PART NUMBERS

■ 042TYPE(01005 case size) -

【温度特性 Temp.char. BJ:B/X5R】

定格電圧 Rated Voltage	形 名 Ordering code		EHS (Environmental Hazardous Substances)	公 称 静電容量 Capacitance 〔pF〕	温度特性 Temperature characteristics	tan δ Dissipation factor (%) Max.	実装条件 Soldering method R:リフロー Reflow soldering W: フロー Wave soldering	静電容量 許 容 差 Capacitance tolerance	厚み Thickness (mm) (inch)
	LMK042 BJ101 ☐ C		RoHS	100					
	LMK042 BJ151 ☐ C		RoHS	150					
	LMK042 BJ221 ☐ C		RoHS	220					
10V	LMK042 BJ331 □ C		RoHS	330		5		± 10%	0.2 ± 0.02
	LMK042 BJ471 ☐ C		RoHS	470					
	LMK042 BJ681 ☐ C		RoHS	680					
	LMK042 BJ102 ☐ C		RoHS	1000	B/X5R* ²		R		
	JMK042 BJ152 ☐ C*1		RoHS	1500	B/XOIT		,,,	± 20%	(0.008 ± 0.001)
	JMK042 BJ222 □ C*1		RoHS	2200					
6.3V	JMK042 BJ332 □ C*1		RoHS	3300		10			
0.37	JMK042 BJ472 □ C*1		RoHS	4700	1	10			
	JMK042 BJ682 □ C*1		RoHS	6800					
	JMK042 BJ103 ☐ C*1		RoHS	10000					

形名の□には静電容量許容差記号が入ります。

- *1 高温負荷試験の試験電圧は定格電圧の 1.5 倍
- *2 個別仕様の取交しにより、X7R/X7S仕様に対応している場合があります。
- \square Please specify the capacitance tolerance code.
- *1 Test Voltage of Loading at high temperature test is 1.5 time of the rated
- *2 We may provide X7R/X7S for some items according to the individual specification.

■ 063TYPE(0201 case size)

【温度特性 Temp.char. BJ:B/X5R】

定格電圧 Rated Voltage	形 名 Ordering code	EHS (Environmental Hazardous Substances)	公 称 静電容量 Capacitance 〔pF〕	温度特性 Temperature characteristics	tan δ Dissipation factor [%] Max.	実装条件 Soldering method R:リフロー Reflow soldering W: フロー Wave soldering	静電容量 許 容 差 Capacitance tolerance	厚み Thickness (mm) (inch)
	TMK063 BJ101□P	RoHS	100					
	TMK063 BJ151□P	RoHS	150					
	TMK063 BJ221□P 5V TMK063 BJ331□P	RoHS	220]				
25V		RoHS	330		3.5			
	TMK063 BJ471□P	RoHS	470					
	TMK063 BJ681□P	RoHS	680					
	TMK063 BJ102□P	RoHS	1000	B/X5R* ²				
	EMK063 BJ152□P	RoHS	1500	D/AOR			±10% ±20%	0.3±0.03
16V	EMK063 BJ222□P	RoHS	2200					
	EMK063 BJ332□P	RoHS	3300		5			
	LMK063 BJ472□P	RoHS	4700		5			
	LMK063 BJ682□P	RoHS	6800			R		
	LMK063 BJ103□P	RoHS	10000					(0.012 ± 0.001)
10V	LMK063 BJ223□P*1	RoHS	22000		7.5			
	LMK063 BJ473□P*1	RoHS	47000		7.5			
	LMK063 BJ104□P*1	RoHS	100000]	10			
	JMK063 BJ473□P*1	RoHS	47000		7.5			
6.3V	JMK063 BJ104□P* ¹	RoHS	100000	VED				
	JMK063 BJ224MP*1,*3	RoHS	220000	X5R				
	AMK063 BJ224MP*1	RoHS	220000		10		±20%	
4V	AMK063 BJ334MP* ^{1,*3}	RoHS	330000				±20%	
	AMK063 BJ474MP*1,*3	RoHS	470000					

形名の□には静電容量許容差記号が入ります。

- *1 高温負荷試験の試験電圧は定格電圧の 1.5 倍
- *2 個別仕様の取交しにより、X7R仕様に対応している場合があります。
- *3 ご使用の回路や機器により、個別仕様の取り交わしが必要になります。 必ず正規販売チャンネルにお問い合わせください。
- $\hfill \square$ Please specify the capacitance tolerance code.
- *1 Test Voltage of Loading at high temperature test is 1.5 time of the rated volt-
- *2 We may provide X7R for some items according to the individual specification.
- *3 The exchange of individual specification is necessary depending on the application and circuit condition. Please contact Taiyo Yuden sales channel.

■ 105TYPE(0402 case size)

【温度特性 Temp.char. BJ:B/X5R】

定格電圧 Rated Voltage	形 名 Ordering code	· H	EHS vironmental lazardous lbstances)	公 称 静電容量 Capacitance 〔pF〕	温度特性 Temperature characteristics	tan δ Dissipation factor [%] Max.	実装条件 Soldering method R:リフロー Reflow soldering W: フロー Wave soldering	静電容量 許 容 差 Capacitance tolerance	厚み Thickness 〔mm〕 (inch)
	UMK105 BJ221□V		RoHS	220					
	UMK105 BJ331□V		RoHS	330					
	UMK105 BJ471□V		RoHS	470					
	UMK105 BJ681□V		RoHS	680					
	UMK105 BJ102□V	I	RoHS	1000		2.5			
50V	UMK105 BJ152□V		RoHS	1500	B/X5R*2	2.5			
	UMK105 BJ222□V		RoHS	2200					
	UMK105 BJ332□V		RoHS	3300					
	UMK105 BJ472 V UMK105 BJ682 V*1 UMK105 BJ103 V 35V GMK105 BJ104 V*1 TMK105 BJ682 V		RoHS	4700					
		I	RoHS	6800					
			RoHS	10000		3.5			
35V			RoHS	100000	B/X5R	5			
			RoHS	6800		2.5			
	TMK105 BJ103□V		RoHS	10000	B/X5R* ²			±10%	0.5±0.05 (0.02±0.002)
	TMK105 BJ153□V		RoHS	15000					
	TMK105 BJ223□V	I	RoHS	22000		3.5			
	TMK105 BJ333 □ V*1		RoHS	33000				±20%	
	TMK105 BJ473□V*1		RoHS	47000			R		
	TMK105 BJ104□V*1	ı	RoHS	100000	B/X5R	5	n		
	EMK105 BJ333 □V	1	RoHS	33000	B/X5R* ²	0.5			
	EMK105 BJ473□V		RoHS	47000	B/X5H [^]	3.5			
16V	EMK105 BJ683 ☐ V		RoHS	68000	B/X5R				
	EMK105 BJ104□V*1		RoHS	100000	B/X5R*2				
	EMK105 BJ224 □ V*1	ı	RoHS	220000		5			
	LMK105 BJ104□V	1	RoHS	100000	B/X5R				
	LMK105 BJ224□V*1	ı	RoHS	220000					
10V	LMK105 BJ474 V*1	1	RoHS	470000					
	LMK105 BJ105□V*1		RoHS	1000000	X5R	10			
	JMK105 BJ224□V*1	1	RoHS	220000	B/X5R	5			
	JMK105 BJ474□V* ¹	ı	RoHS	470000					
6.3V	3V JMK105 BJ105□V*1	ı	RoHS	1000000					
	JMK105 BJ225MV*1,*3	1	RoHS	2200000	X5R	10			
	AMK105 BJ335MV*1,*3		RoHS	3300000	AJN	10		±20%	
4V	AMK105 BJ475MV*1,*3		RoHS	4700000				±2070	0.5±0.1 (0.02±0.00

形名の□には静電容量許容差記号が入ります。

^{*1} 高温負荷試験の試験電圧は定格電圧の 1.5 倍

^{*2} 個別仕様の取交しにより、X7R仕様に対応している場合があります。

^{*3} ご使用の回路や機器により、個別仕様の取り交わしが必要になります。 必ず正規販売チャンネルにお問い合わせください。

 $[\]square$ Please specify the capacitance tolerance code.

^{*1} Test Voltage of Loading at high temperature test is 1.5 time of the rated volt-

^{*2} We may provide X7R for some items according to the individual specification.

^{*3} The exchange of individual specification is necessary depending on the application and circuit condition. Please contact Taiyo Yuden sales channel.

アイテム一覧 PART NUMBERS

【温度特性 Temp.char. B7:X7R】

定格電圧 Rated Voltage	形 名 Ordering code	EHS (Environmental Hazardous Substances)	公 称 静電容量 Capacitance 〔pF〕	温度特性 Temperature characteristics	tan δ Dissipation factor (%) Max.	実装条件 Soldering method R:リフロー Reflow soldering W: フロー Wave soldering	静電容量 許 容 差 Capacitance tolerance	厚み Thickness (mm) (inch)
	UMK105 B7 221 □ V	RoHS	220					
	UMK105 B7 331□V	RoHS 330						
	UMK105 B7 471□V	RoHS	470					
	UMK105 B7 681□V	RoHS	680					
	UMK105 B7 102□V	RoHS	1000		2.5			
50V	UMK105 B7 152□V	RoHS	1500		2.5			
	UMK105 B7 222 □ V	RoHS	2200					
	UMK105 B7 332 □ V	RoHS	3300	-			±10%	0.5±0.05
	UMK105 B7 472 UV*1	RoHS	4700					
	UMK105 B7 682 Uv ^{*1}	RoHS	6800					
	UMK105 B7 103 □ V*1	RoHS	10000		3.5			
	TMK105 B7 472 UV	RoHS	4700	X7R	2.5	R		
	TMK105 B7 682 □ V	RoHS	6800		2.5		±20%	(0.02 ± 0.002)
	TMK105 B7 103□V	RoHS	10000					
25V	TMK105 B7 153 U*1	RoHS	15000					
	TMK105 B7 223 □ V*1	RoHS	22000					
	TMK105 B7333□V*1	RoHS	33000					
	TMK105 B7 473 □ V*1	RoHS	47000		3.5			
	EMK105 B7153□V	RoHS	15000					
	EMK105 B7223□V	RoHS	22000					
16V	EMK105 B7333□V	RoHS	33000					
	EMK105 B7473□V	RoHS	47000					
	EMK105 B7 104 □ V*1	RoHS	100000		5			

形名の□には静電容量許容差記号が入ります。

【温度特性 Temp.char. F:Y5V】

定格電圧 Rated Voltage	形 名 Ordering code	EHS (Environmental Hazardous Substances)	公 称 静電容量 Capacitance 〔pF〕	温度特性 Temperature characteristics	tan δ Dissipation factor (%) Max.	実装条件 Soldering method R:リフロー Reflow soldering W: フロー Wave soldering	静電容量 許 容 差 Capacitance tolerance	厚み Thickness (mm) (inch)
50V	UMK105 F103ZV	RoHS	10000		5			
25V	TMK105 F223ZV	RoHS	22000		5		1.000/	0.5.1.0.05
16V	EMK105 F473ZV	RoHS	47000		7			
100	EMK105 F104ZV	RoHS	100000	F/Y5V	9	R	+80% -20%	0.5 ± 0.05 (0.02 ± 0.002)
10V	LMK105 F224ZV	RoHS	220000		11		-20%	(0.02 ± 0.002)
0.01/	JMK105 F474ZV	RoHS	470000		12.5			
6.3V	JMK105 F105ZV*1	RoHS	1000000		20			

^{*1} 高温負荷試験の試験電圧は定格電圧の 1.5 倍

^{*1} 高温負荷試験の試験電圧は定格電圧の 1.5 倍

 $[\]hfill \square$ Please specify the capacitance tolerance code.

^{*1} Test Voltage of Loading at high temperature test is 1.5 time of the rated voltage.

 $^{^{\}star}1$ Test Voltage of Loading at high temperature test is 1.5 time of the rated voltage.

梱包 PACKAGING

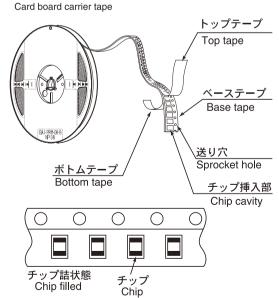
①最小受注単位数 Minimum Quantity

■テーピング梱包 Taped packaging

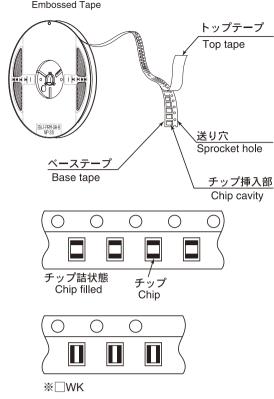
■ナーヒング梱記	raped packaging			
形式(EIA) Type	製品厚み Thickness			数量 d quantity cs]
Турс	mm (inch)	code	紙テープ paper	エンボステープ Embossed tape
□MK042 (01005)	0.2 (0.008)	С	15000	_
☐MK063(0201)	0.3 (0.012)	Р	15000	_
□2K096(0302)	0.3 (0.012)	Р	10000	
ZK096(030Z)	0.45 (0.018)	K	10000	_
□WK105(0204)	0.3 (0.012)	Р	10000	_
☐MK105(0402)	0.5 (0.020)	V, W	10000	
□VK105 (0402)	0.5 (0.020)	W	10000	_
	0.45 (0.018)	K	4000	_
☐MK107(0603) ☐WK107(0306)	0.5 (0.020)	V	_	4000
_WIC107 (0300)	0.8(0.031)	Α	4000	_
	0.5 (0.020)	V	4000	_
□2K110(0504)	0.8(0.031)	А	4000	_
	0.6 (0.024)	В	4000	_
	0.45 (0.018)	K	4000	_
☐MK212(0805) ☐WK212(0508)	0.85 (0.033)	D	4000	_
_W16212(0000)	1.25 (0.049)	G	_	3000
□4K212(0805)	0.85 (0.033)	D	4000	_
□2K212(0805)	0.85 (0.033)	D	4000	_
	0.85 (0.033)	D	4000	_
□ • #1404.0/4.000\	1.15 (0.045)	F		3000
□MK316(1206)	1.25 (0.049)	G		3000
	1.6 (0.063)	L	_	2000
	0.85 (0.033)	D		
	1.15 (0.045)	F		2000
□MK325(1210)	1.5 (0.059)	Н	_	2000
□INIV352(1510)	1.9 (0.075)	N		
	2.0max (0.079)	Y	_	2000
	2.5 (0.098)	М	_	500(T), 1000(P)
☐MK432(1812)	2.5 (0.098)	М	_	500

②テーピング材質 Taping material 紙テープ

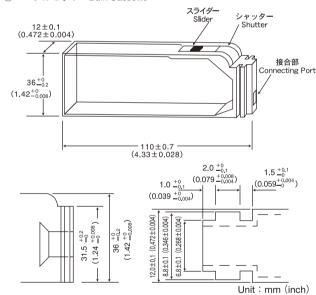
※プレスポケットタイプは、 ボトムテープ無し。





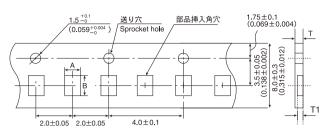


③バルクカセット Bulk Cassette



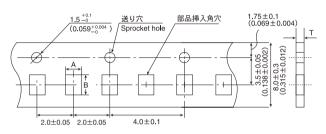
105, 107, 212形状で個別対応致しますのでお問い合せ下さい。 Please contact any of our offices for accepting your requirement according to dimensions 0402, 0603, 0805.(inch)

③テーピング寸法 Taping dimensions 紙テープ Paper Tape(8mm幅)(0.315inches wide)



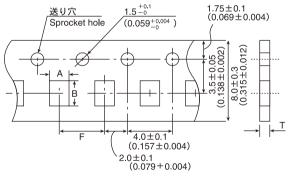
Type		挿入部	挿入ピッチ	テープ厚み		
(EIA)		Cavity	Insertion Pitch	Tape Thickness		
(ETA)	Α	В	F	Т	T1	
☐MK042(01005)	0.25	0.45	2.0±0.05	0.36max.	0.27max.	
	(0.010)	(0.018)	(0.079±0.002)	(0.014)	(0.011)	
☐MK063(0201)	0.37	0.67	2.0±0.05	0.45max.	0.42max.	
	(0.016)	(0.027)	(0.079±0.002)	(0.018)	(0.017)	
□WK105(0204)	0.65	1.15	2.0±0.05	0.45max	0.42max	
	(0.026)	(0.045)	(0.079±0.002)	(0.018max)	(0.017max)	

Unit: mm (inch)



T	チッフ	[°] 挿入部	挿入ピッチ	テープ厚み
Type (EIA)	Chip Cavity		Insertion Pitch	Tape Thickness
(EIA)	Α	В	F	Т
	0.72	1.02	2.0±0.05	0.45max.(0.018max)
□2K096(0302)	(0.028)	(0.040)	(0.079±0.002)	0.6max.(0.024max)
☐MK105(0402)	0.65	1.15	2.0±0.05	0.8max.
□VK105(0402)	(0.026)	(0.045)	(0.079±0.002)	(0.031max.)

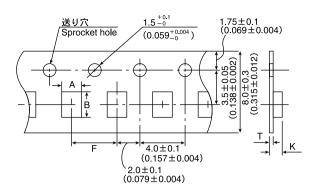
Unit: mm (inch)



_	チッフ	"挿入部	挿入ピッチ	テープ厚み
Type	Chip (Cavity	Insertion Pitch	Tape Thickness
(EIA)	Α	В	F	Т
☐MK107(0603)	1.0	1.8	4.0±0.1	1.1max.
□WK107(0306)	(0.039)	(0.071)	(0.157±0.004)	(0.043max.)
	1.15	1.55	4.0±0.1	1.0max.
□2K110 (0504)	(0.045)	(0.061)	(0.157±0.004)	(0.039max.)
☐MK212(0805)				
□WK212 (0508)	1.65	2.4		
□4K212(0805)	(0.065)	(0.094)	4.0±0.1	1.1max.
□2K212(0805)			(0.157±0.004)	(0.043max.)
□MK316(1206)	2.0	3.6		
□IVIN3 I0 (1200)	(0.079)	(0.142)		

Unit: mm (inch)

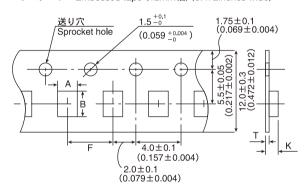
エンボステープ Embossed tape (8mm幅) (0.315inches wide)



チップ挿入部		挿入ピッチ テーフ		プ厚み
Chip	cavity	Insertion Pitch	Tape Th	ickness
А	В	F	K	Т
1.0	1.8		1.3max.	0.25±0.1
(0.039)	(0.071)		(0.051max.)	(0.01±0.004)
1.65	2.4			
(0.065)	(0.094)	4.0±0.1		
2.0	3.6	(0.157±0.004)	3.4max.	0.6max.
(0.079)	(0.142)		(0.134max.)	(0.024max.)
2.8	3.6	1		
(0.110)	(0.142)			
	Chip (A 1.0 (0.039) 1.65 (0.065) 2.0 (0.079) 2.8	Chip cavity A B 1.0 1.8 (0.039) (0.071) 1.65 2.4 (0.065) (0.094) 2.0 3.6 (0.079) (0.142) 2.8 3.6	Chip cavity Insertion Pitch A B F 1.0 1.8 (0.039) (0.071) 1.65 2.4 (0.065) (0.094) 4.0±0.1 2.0 3.6 (0.157±0.004) (0.079) (0.142) 2.8 3.6	Chip cavity Insertion Pitch Tape Th A B F K 1.0 1.8 1.3max. (0.039) (0.071) (0.051max.) 1.65 2.4 (0.065) (0.065) (0.094) 4.0±0.1 2.0 3.6 (0.157±0.004) (0.079) (0.142) 2.8 3.6

Unit: mm (inch)

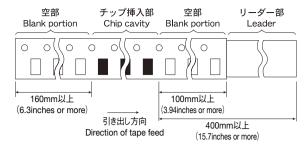
エンボステープ Embossed tape (12mm幅) (0.472inches wide)



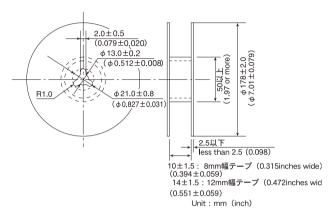
Туре			挿入ピッチ Insertion Pitch		. •
(EIA)	A B		F	K	Т
□MK432 (1812)	3.7 (0.146)	4.9 (0.193)	8.0±0.1 (0.315±0.004)	4.0max. (0.157max.)	0.6max. (0.024max.)

Unit: mm (inch)

④リーダー部/空部 Leader and Blank portion

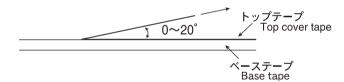


⑤リール寸法 Reel size



⑥トップテープ強度 Top Tape Strength

トップテープのはがし力は下図矢印方向にて0.1~0.7Nとなります。 The top tape requires a peel-off force of 0.1~0.7N in the direction of the arrow as illustrated below.



Multilayer Ceramic Capacitor Chips

		Specifi	ed Value		
Item	Temperature Comp	pensating (Class 1)	High Permiti	vity (Class 2)	Test Methods and Remarks
	Standard	High Frequency Type	Standard Note1	High Value	
I.Operating Temperature Range	-55 to +125°C		BJ: −55 to +125°C F: −25 to +85°C	−25 to +85°C	High Capacitance Type BJ (X7R): -55~+125°C, BJ (X5R): -55~+85° E (Y5U): -30~+85°C, F (Y5V): -30~+85°
Storage Temperature. Range	-55 to +125°C		BJ: -55 to +125°C F: -25 to +85°C	-25 to +85°C	$\label{eq:high-Capacitance-Type} \begin{array}{ll} \text{High-Capacitance-Type} & \text{BJ} \ (X7R) : -55 \sim +125^{\circ}\text{C}, \ \text{BJ} \ (X5R) : -55 \sim +85^{\circ}\\ & \text{E} \ (Y5U) : -30 \sim +85^{\circ}\text{C}, \text{F} \ (Y5V) : -30 \sim +85^{\circ}\\ \end{array}$
B.Rated Voltage	50VDC,25VDC, 16VDC	16VDC 50VDC	50VDC,25VDC	50VDC,35VDC,25VDC 16VDC,10VDC,6.3VDC 4DVC, 2.5VDC	
l.Withstanding Voltage Between terminals	No breakdown or damage	No abnormality	No breakdown or dama	age	Applied voltage: Rated voltage ×3 (Class 1) Rated voltage ×2.5 (Class 2) Duration: 1 to 5 sec. Charge/discharge current: 50mA max. (Class 1,2)
5.Insulation Resistance	10000 MΩ min.		500 M Ω μ F. or 10000 smaller. Note 5	$\mbox{M}\Omega.,$ whichever is the	Applied voltage: Rated voltage Duration: 60±5 sec. Charge/discharge current: 50mA max.
6.Capacitance (Tolerance)	0.5 to 5 pF: ±0.25 pF 1 to 10pF: ±0.5 pF 5 to 10 pF: ±1 pF 11 pF or over: ± 5% ±10% 105TYPERA, SA, TA, UA only 0.5~2pF: ±0.1pF 2.2~20pF: ±5%	0.5 to 2 pF: ±0.1 pF 2.2 to 5.1 pF: ±5%	BJ: ±10%, ±20% F: +80% -20	BJ: ±10%, ±20% F: -20%/+80%	Measuring frequency : Class1 : 1MHz±10% (C≦1000pF) 1 k Hz±10% (C≤1000pF) Class2 : 1 k Hz±10% (C≤10 μ F) 120Hz±10Hz (C>10 μ F) 120Hz±10Hz (C>10 μ F) Measuring voltage : Note 4 Class1 : 0.5~5Vrms (C≤1000pF) 1±0.2Vrms (C>1000pF) Class2 : 1±0.2Vrms (C≤10 μ F) 0.5±0.1Vrms (C>10 μ F) 0.5±0.1Vrms (C>10 μ F) Elias application: None N
7.Q or Tangent of Loss Angle $(an \delta)$	Under 30 pF : Q≥400 + 20C 30 pF or over : Q≥1000 C= Nominal capacitance	Refer to detailed specification	BJ: 2.5% max. (50V, 25V) F: 5.0% max. (50V, 25V) Note 4	BJ: 2.5% max. F: 7% max. Note 4	Multilayer: Measuring frequency: $ \begin{array}{c} \text{Multilayer:} \\ \text{Measuring frequency:} \\ \text{Class1: } 1 \text{MHz} \pm 10\% ($C \! \! \! \! \! \! \! \! \! \! \! \! \! \! \! \! \! \! \!$
3.Temperature (Without Characteristic voltage apof Capacitance plication)	CK: 0±250 CJ: 0±120 CH: 0±60 CG: 0±30 RH: -220±60 SK: -330±250 SJ: -330±120 SH: -330±60 TK: -470±250 TJ: -470±120 UK: -750±250 UJ: -750±120 SL: +350 to -1000 (ppm/C)	CH: 0±60 RH: -220±60 (ppm/°C)	BJ: ±10% (-25~85°C) F: +30% (-25~85°C) BJ (X7R): ±15% F (Y5V): +22% -82	BJ: ±10% (-25~+85°C) F: +30%/-80% (-25~+85°C) BJ (X7R, X5R): ±15% F (Y5V): +22%/-82%	According to JIS C 5102 clause 7.12. Temperature compensating: Measurement of capacitance at 20°C and 85°C shall be made to calculate temperature characteristic by the following equation. \(\frac{C_{80} - C_{20}}{C_{20} \times \times T} \times 10^6 \times
2.Resistance to Flexure of Substrate	Appearance: No abnormality Capacitance change: Within ±5% or ±0.5 pF, whichever is larger.	Appearance: No abnormality Capacitance change: Within±0.5 pF	Appearance: No abnormality Capacitance change: BJ: Within ±12.5% F: Within ±30%		Warp: 1mm Testing board: glass epoxy—resin substrate Thickness: 1.6mm (063 TYPE: 0.8mm) The measurement shall be made with board in the bent position. Board R-230 Warp Warp

Multilayer Ceramic Capacitor Chips

		Specifie	u value		
Item	Temperature Comp	ensating (Class 1)	High Permittiv	vity (Class 2)	Test Methods and Remarks
	Standard	High Frequency Type	Standard Note1	High Value	
0.Body Strength	_	No mechanical damage.	_	_	High Frequency Multilayer: Applied force: 5N Duration: 10 sec. Press R0.5 Pressing jig Chip (LW Reverse)
1.Adhesion of Electrode	No separation or indicat	ion of separation of elect	rode.		Applied force: 5N Duration: 30±5 sec. (01005, 0201, 0302 TYPE 2N) Hooked jig R-05 Chip Cross-section
2.Solderability	At least 95% of terminal	electrode is covered by	new solder.		Solder temperature: 230±5℃
3.Resistance to soldering	Appearance: No abnormality Capacitance change: Within ± 2.5% or	Appearance: No abnormality Capacitance change: Within ±2.5%	Appearance: No abnorm Capacitance change: W W tan δ: Initial value		Duration: 4±1 sec. Preconditioning: Thermal treatment (at 150°C for 1 hr) (Applicable to Class 2.) Solder temperature: 270±5°C Duration: 3±0.5 sec.
± lax Q: In In W	±0.25pF, whichever is larger. Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality			Preheating conditions: 80 to 100°C, 2 to 5 min. or 5 to 10 min. $150 \text{ to } 200^\circ\text{C}, 2 \text{ to 5 min. or 5 to 10 min.}$ Recovery: Recovery for the following period under the standard condition after the test. $6{\sim}24 \text{ hrs (Class 1)}$ $24{\pm}2 \text{ hrs (Class 2)}$
4.Thermal shock	Appearance: No abnormality Capacitance change: Within ±2.5% or ±0.25pF, whichever is larger. Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	Appearance: No abnormality Capacitance change: Within ±0.25pF Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	Appearance: No abnormality Capacitance change: Within $\pm 7.5\%$ (BJ) Within $\pm 20\%$ (F) tan δ : Initial value Note 4 Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality		Preconditioning: Thermal treatment (at 150°C for 1 hr) (Applicable to Class 2.) Conditions for 1 cycle: Step 1: Minimum operating temperature +0 °C 30±3 min. Step 2: Room temperature 2 to 3 min. Step 3: Maximum operating temperature -0 °C 30±3 min. Step 4: Room temperature 2 to 3 min. Number of cycles: 5 times Recovery after the test: 6~24 hrs (Class 1) 24±2 hrs (Class 2)
5.Damp Heat (steady state)	Appearance: No abnormality Capacitance change: Within $\pm 5\%$ or ± 0.5 pF, whichever is larger. Q: $C \ge 30$ pF : $Q \ge 350$ $10 \le C < 30$ pF: $Q \ge 275 + 2.5$ C $C < 10$ pF : $Q \ge 200$ $+ 10$ C C: Nominal capacitance Insulation resistance: 1000 M Ω min.	Appearance: No abnormality Capacitance change: Within $\pm 0.5 pF$, Insulation resistance: $1000 \ M\Omega \ min$.	normality normality Capacitance change: BJ: Within ±12.5% BJ:Within ±12.5%		Multilayer: Preconditioning: Thermal treatment (at 150°C for 1 hr) (Applicable to Class 2.) Temperature: 40 ± 2 °C Humidity: 90 to 95% RH Duration: 500^{+24}_{-0} hrs Recovery: Recovery for the following period under the standard condition after the removal from test chamber. $6\sim24$ hrs (Class 1) 24 ± 2 hrs (Class 2) High—Frequency Multilayer: Temperature: 60 ± 2 °C Humidity: 90 to 95% RH Duration: 500^{+24}_{-0} hrs Recovery: Recovery for the following period under the standard condition after the removal from test chamber. $6\sim24$ hrs (Class 1)

Multilayer Ceramic Capacitor Chips

		Specifie	ed Value			
Item	Temperature Compensating (Class 1)		High Permittiv	vity (Class 2)	Test Methods and Remarks	
	Standard	High Frequency Type	Standard Note1	High Value		
16.Loading under Damp Heat	Appearance: No abnormality Capacitance change: Within ±7.5% or ± 0.75pF, whichever is larger. Q: C≧30 pF: Q≧200 C<30 pF: Q≧100 + 10C/3 C: Nominal capacitance Insulation resistance: 500 MΩ min.	Appearance: No abnormality Capacitance change: C≤2 pF: Within ±0.4 pF C>2 pF: Within ±0.75 pF C: Nominal capacitance Insulation resistance: 500 MΩ min.	Appearance: No abnormality Capacitance change: BJ: Within $\pm 12.5\%$ F: Within $\pm 30\%$ Note 4 tan δ : BJ: 5.0% max. F: 7.5% max. Note 4 Insulation resistance: $25~\text{M}\Omega\mu\text{F}$ or $500~\text{M}\Omega$, whichever is the smaller. Note 5	Appearance: No abnormality Capacitance change: BJ: Within $\pm 12.5\%$ F: Within $\pm 30\%$ Note 4 tan δ : BJ: 5.0% max. F: 11% max. Note 4 Insulation resistance: $25~\mathrm{M}\Omega\mu\mathrm{F}$ or $500~\mathrm{M}\Omega$, whichever is the smaller. Note 5	According to JIS C 5102 Clause 9. 9. Multilayer: Preconditioning: Voltage treatment (Class 2) Temperature: 40±2°C Humidity: 90 to 95% RH Duration: 500 +24 hrs Applied voltage: Rated voltage Charge and discharge current: 50mA max. (Class 1,2) Recovery: Recovery for the following period under the standar condition after the removal from test chamber. 6-24 hrs (Class 1) 24±2 hrs (Class 2) High—Frequency Multilayer: Temperature: 60±2°C Humidity: 90 to 95% RH Duration: 500 +24 hrs Applied voltage: Rated voltage Charge and discharge current: 50mA max. Recovery: 6~24 hrs of recovery under the standar condition after the removal from test chamber	
17.Loading at High Temperature	Appearance: No abnormality Capacitance change: Within ±3% or ±0.3pF, whichever is larger. Q: C≧30 pF: Q≧250 10≦C<30 pF: Q≧275 +2.5C C<10 pF: Q≧200 + 10C C: Nominal capacitance Insulation resistance: 1000 MΩ min.	Appearance: No abnormality Capacitance change: Within ±3% or ± 0.3pF, whichever is larger. Insulation resistance: 1000 MΩ min.	Appearance: No abnormality Capacitance change: BJ: Within $\pm 12.5\%$ F: Within $\pm 30\%$ Note 4 tan δ : BJ: 4.0% max. F: 7.5% max. Note 4 Insulation resistance: $50~\mathrm{M}\Omega~\mu~\mathrm{F}$ or $1000~\mathrm{M}\Omega$, whichever is smaller. Note 5	Appearance: No abnormality Capacitance change: BJ: Within $\pm 12.5\%$ Within $\pm 20\% * \%$ Within $\pm 25\% * \%$ F: Within $\pm 30\%$ Note 4 $\tan \delta$: BJ: 5.0% max. F: 11% max. Note 4 Insulation resistance: $50 \ M\Omega \ \mu$ F or $1000 \ M\Omega$, whichever is smaller. Note 5	According to JIS C 5102 clause 9.10. Multilayer: Preconditioning: Voltage treatment (Class 2) Temperature:125±3°C (Class 1, Class 2: B, BJ (X7R)) 85±2°C (Class 2: BJ,F) Duration: 1000 ^{4,46} hrs Applied voltage: Rated voltage×2 Note 6 Recovery: Recovery for the following period under the standard condition after the removal from test chamber: 6~24 hrs (Class 1) 24±2 hrs (Class 2) High—Frequency Multilayer: Temperature: 125±3°C (Class 1) Duration: 1000, ^{4,48} hrs Applied voltage: Rated voltage×2 Recovery: 6~24 hrs of recovery under the standard condition after the removal from test chamber.	

Note 1 :For 105 type, specified in "High value".

Note 2 :Thermal treatment (Multilayer): 1 hr of thermal treatment at 150 +0 /- 10 °C followed by 24±2 hrs of recovery under the standard condition shall be performed before the measurement.

Note 3 :Voltage treatment (Multilayer): 1 hr of voltage treatment and voltage for testing followed by 24±2 hrs of recovery under the standard condition shall be performed before the measurement.

Note 4, 5 :The figure indicates typical inspection. Please refer to individual specifications.

Note 6 :Some of the parts are applicable in rated voltage × 1.5. Please refer to individual specifications.

Note on standard condition: "standard condition" referred to herein is defined as follows: 5 to 35°C of temperature, 45 to 85% relative humidity, and 86 to 106kPa of air pressure.

When there are questions concerning measurement results: In order to provide correlation data, the test shall be conducted under condition of 20±2°C of temperature, 60 to 70% relative humidity, and 86 to 106kPa of air pressure. Unless otherwise specified, all the tests are conducted under the "standard condition."

Verification of operating environment, electrical rating and performance 1. A malfunction in medical equipment, spacecraft, nuclear reactors, etc. may cause serious harm to human life or have severe social ramifications. As such, any capacitors to be used in such equipment may require higher safety and/or reliability considerations and should be clearly differentiated from components used in general purpose applications. Operating Voltage (Verification of Rated voltage) 1. The operating voltage for capacitors must always be lower than their rated values. If an AC voltage is loaded on a DC voltage, the sum of the two peak voltages should be lower than the rated value of the capacitor chosen. For a circuit where both an AC and a pulse voltage may be present, the sum of their peak voltages should also be lower than the capacitor's rated voltage.	
 Even if the applied voltage is lower than the rated value, the reliability of capacitors might be reduced if either a high fre- quency AC voltage or a pulse voltage having rapid rise time is present in the circuit. 	
Pattern configurations (Design of Land-patterns) 1. When capacitors are mounted on a PCB, the amount of solder used (size of fillet) can directly affect capacitor performance. Therefore, the following items must be carefully considered in the design of solder land patterns: (1) The amount of solder applied can affect the ability of chips to withstand mechanical stresses which may lead to breaking or cracking. Therefore, when designing land-patterns it is necessary to consider the appropriate size and configuration of the solder pads which in turn determines the amount of solder necessary to form the fillets. (2) When more than one part is jointly soldered onto the same land or pad, the pad must be designed so that each component's soldering point is separated by solder-resist.	1.The following diagrams and tables show some examples of recommended patterns prevent excessive solder amourts. (larger fillets which extend above the compone end terminations) Examples of improper pattern designs are also shown. (1) Recommended land dimensions for a typical chip capacitor land patterns for PCB Land pattern Chip capacitor Chip capacitor Solder-resist Chip capacitor Chip capacitor Chip capacitor Chip capacitor Size L 1.6 2.0 3.2 3.2 W 0.8 1.25 1.6 2.5 A 0.8~1.0 1.0~1.4 1.8~2.5 1.8~2.5 B 0.5~0.8 0.8~1.5 0.8~1.7 0.8~1.7 C 0.6~0.8 0.9~1.2 1.2~1.6 1.8~2.5 Recommended land dimensions for reflow-soldering (unit: mm) Type 042 063 105 107 212 316 325 432 Recommended land dimensions for reflow-soldering (unit: mm) Type 042 063 105 107 212 316 325 432 L 0.4 0.6 1.0 1.6 2.0 3.2 3.2 4.5 Size L 0.4 0.6 1.0 1.6 2.0 3.2 3.2 4.5 A 0.15~0.25 0.20~0.30 0.45~0.55 0.8~1.0 0.8~1.2 1.8~2.5 1.8~2.5 2.5~3 B 0.10~0.20 0.20~0.30 0.45~0.55 0.8~1.0 0.8~1.2 1.0~1.5 1.0~1.5 1.5~1 C 0.15~0.30 0.25~0.40 0.45~0.55 0.6~0.8 0.9~1.6 1.2~2.0 1.8~3.2 2.3~3 Excess solder can affect the ability of chips to withstand mechanical stresses. Ther
	reliability of capacitors might be reduced if either a high frequency AC voltage or a pulse voltage having rapid rise time is present in the circuit. Pattern configurations (Design of Land-patterns) 1. When capacitors are mounted on a PCB, the amount of solder used (size of fillet) can directly affect capacitor performance. Therefore, the following items must be carefully considered in the design of solder land patterns: (1) The amount of solder applied can affect the ability of chips to withstand mechanical stresses which may lead to breaking or cracking. Therefore, when designing land-patterns it is necessary to consider the appropriate size and configuration of the solder pads which in turn determines the amount of solder necessary to form the fillets. (2) When more than one part is jointly soldered onto the same land or pad, the pad must be designed so that each

d

Stages	Precautions		Technical considera	ations
CB Design		Chip can C ↑	B A B 105 107 212 52 0.8 1.25 0 1.6 2.0 -0.22 0.25~0.3 0.5~0.7 0.25 0.3~0.4 0.4~0.5	
		Items	Not recommended	Recommended
		Mixed mounting of SMD and leaded compo- nents	Lead wire of component	Solder-resist
		Component placement close to the chassis	Chassis Solder(for grounding)	Solder-resist
		Hand-soldering of leaded components near mounted components	Lead wire of component- Soldering iron	Solder-resist —
		Horizontal component placement		Solder-resist

Pattern configurations

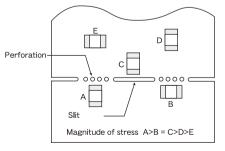
(Capacitor layout on panelized [breakaway] PC boards)

1. After capacitors have been mounted on the boards, chips can be subjected to mechanical stresses in subsequent manufacturing processes (PCB cutting, board inspection, mounting of additional parts, assembly into the chassis, wave soldering the reflow soldered boards etc.) For this reason, planning pattern configurations and the position of SMD capacitors should be carefully performed to minimize stress.

1-1. The following are examples of good and bad capacitor layout; SMD capacitors should be located to minimize any possible mechanical stresses from board warp or deflection.

	Not recommended	Recommended
Deflection of the board		Position the component at a right angle to the direction of the mechanical stresses that are anticipated.

1-2. To layout the capacitors for the breakaway PC board, it should be noted that the amount of mechanical stresses given will vary depending on capacitor layout. The example below shows recommendations for better design.



1-3. When breaking PC boards along their perforations, the amount of mechanical stress on the capacitors can vary according to the method used. The following methods are listed in order from least stressful to most stressful: push-back, slit, V-grooving, and perforation. Thus, any ideal SMD capacitor layout must also consider the PCB splitting procedure.

Stages	Precautions		Technical consider	ations
3.Considerations for auto- matic placement	Adjustment of mounting machine 1. Excessive impact load should not be imposed on the capacitors when mounting onto the PC boards. 2. The maintenance and inspection of the mounters should be conducted periodically.	capacitors, cau before lowering (1) The lower limi PC board after (2) The pick-up pr (3) To reduce the nozzle, support	sing damage. To avoid this, the fithe pick-up nozzle: t of the pick-up nozzle should be correcting for deflection of the bressure should be adjusted between amount of deflection of the boating pins or back-up pins should be	
			Not recommended	Recommended
		Single-sided mounting	Cracks	Supporting pin
		Double-sided mounting	Solder peeling — Cracks—	Supporting pin-
		cracking of the this, the monitor	capacitors because of mechanic ring of the width between the align	e nozzle height can cause chipping al impact on the capacitors. To aven nment pin in the stopped position, a pin should be conducted periodically
	Selection of Adhesives 1. Mounting capacitors with adhesives in preliminary assembly, before the soldering stage, may lead to degraded capacitor characteristics unless the following factors are appropriately checked; the size of land patterns, type of adhesive, amount applied, hardening temperature and hardening period. Therefore, it is imperative to consult the manufacturer of the adhesives on proper usage and amounts of adhesive to use.	the shrinkage p stresses on the adhesive applie lowing precaution (1) Required adhe a. The adhesive s ing & solder pro b. The adhesive sl c. The adhesive sl d. The adhesive sl	percentage of the adhesive and e capacitors and lead to crackin d to the board may adversely affect ons should be noted in the applications should be noted in the applications to the contractoristics hould be strong enough to hold to the contractoristics the strong enough to hold to the contractoristics the contractoristic than contractoristics the contractori	parts on the board during the mounting the mounting the mounting temperatures.
			nust not be contaminated. hould have excellent insulation ch	naracteristics.
		h. The adhesive sl	hould not be toxic and have no en	mission of toxic gasses.
			nded amount of adhesives is as fo	
		Figure	212/316 case size 0.3mm	
		b	100 ~120	
		С	Adhesives should no	
		Amour	at of adhesive A	After capacitors are bonded

Stages	Precautions	Technical considerations
Soldering	Selection of Flux 1. Since flux may have a significant effect on the performance of capacitors, it is necessary to verify the following conditions prior to use; (1) Flux used should be with less than or equal to 0.1 wt% (equivelent to chroline) of halogenated content. Flux having a strong acidity content should not be applied. (2) When soldering capacitors on the board, the amount of flux applied should be controlled at the optimum level. (3) When using water-soluble flux, special care should be taken to properly clean the boards.	1-1. When too much halogenated substance (Chlorine, etc.) content is used to activat the flux, or highly acidic flux is used, an excessive amount of residue after soldering may lead to corrosion of the terminal electrodes or degradation of insulation resistance on the surface of the capacitors. 1-2. Flux is used to increase solderability in flow soldering, but if too much is applied, large amount of flux gas may be emitted and may detrimentally affect solderability. The minimize the amount of flux applied, it is recommended to use a flux-bubbling system 1-3. Since the residue of water-soluble flux is easily dissolved by water content in the air, the residue on the surface of capacitors in high humidity conditions may cause degradation of insulation resistance and therefore affect the reliability of the components. The cleaning methods and the capability of the machines used should also be considered carefully when selecting water-soluble flux.
	Soldering Temperature, time, amount of solder, etc. are specified in accordance with the following recommended conditions.	1-1. Preheating when soldering Heating: Ceramic chip components should be preheated to within 100 to 130°C of the soldering. Cooling: The temperature difference between the components and cleaning process should not be greater than 100°C. Ceramic chip capacitors are susceptible to thermal shock when exposed to rapid or concentrated heating or rapid cooling. Therefore, the soldering process must be conducted witting great care so as to prevent malfunction of the components due to excessive thermal shock.
	Sn-Zn solder paste can affect MLCC reliability performance. Please contact us prior to usage.	Recommended conditions for soldering [Reflow soldering] Temperature profile Temperature To secure To secure To secure Temperature To secure To secure To secure Temperature To secure To secure To secure To secure To secure Temperature To secure
		[Wave soldering] Temperature profile Temperature (°C) (Pb free soldering 300 Peak 260°C max - 250°C 10 sec max 10 sec m

Stages	Precautions	Technical considerations
4. Soldering		[Hand soldering] Temperature profile Temperature (C) (Pb free soldering) 400 300 401 400 300 401 400 300 401 400 300 401 400 400
5.Cleaning	Cleaning conditions 1. When cleaning the PC board after the capacitors are all mounted, select the appropriate cleaning solution according to the type of flux used and purpose of the cleaning (e.g. to remove soldering flux or other materials from the production process.) 2. Cleaning conditions should be determined after verifying, through a test run, that the cleaning process does not affect the capacitor's characteristics.	1. The use of inappropriate solutions can cause foreign substances such as flux residue to adhere to the capacitor or deteriorate the capacitor's outer coating, resulting in a degradation of the capacitor's electrical properties (especially insulation resistance). 2. Inappropriate cleaning conditions (insufficient or excessive cleaning) may detrimentally affect the performance of the capacitors. (1) Excessive cleaning In the case of ultrasonic cleaning, too much power output can cause excessive vibration of the PC board which may lead to the cracking of the capacitor or the soldered portion, or decrease the terminal electrodes' strength. Thus the following conditions should be carefully checked; Ultrasonic output Below 20 W/ & Ultrasonic frequency Below 40 kHz
6.Post cleaning processes	1. With some type of resins a decomposition gas or chemical reaction vapor may remain inside the resin during the hardening period or while left under normal storage conditions resulting in the deterioration of the capacitor's performance. 2. When a resin's hardening temperature is higher than the capacitor's operating temperature, the stresses generated by the excess heat may lead to capacitor damage or destruction. The use of such resins, molding materials etc. is not recommended.	Ultrasonic washing period 5 min. or less
7.Handling	Breakaway PC boards (splitting along perforations) 1. When splitting the PC board after mounting capacitors and other components, care is required so as not to give any stresses of deflection or twisting to the board. 2. Board separation should not be done manually, but by using the appropriate devices. Mechanical considerations 1. Be careful not to subject the capacitors to excessive mechanical shocks. (1) If ceramic capacitors are dropped onto the floor or a hard surface, they should not be used. (2) When handling the mounted boards, be careful that the mounted components do not come in contact with or bump against other boards or components.	

Stages	Precautions	Technical considerations
8.Storage conditions	Storage 1. To maintain the solderability of terminal electrodes and to keep the packaging material in good condition, care must be taken to control temperature and humidity in the storage area. Humidity should especially be kept as low as possible. Recommended conditions Ambient temperature Below 30°C Humidity Below 70% RH The ambient temperature must be kept below 40°C. Even under ideal storage conditions capacitor electrode solderability decreases as time passes, so should be used within 6 months from the time of delivery. Ceramic chip capacitors should be kept where no chlorine or sulfur exists in the air. 2. The capacitance value of high dielectric constant capacitors (type 2 &3) will gradually decrease with the passage of time, so this should be taken into consideration in the circuit design. If such a capacitance reduction occurs, a heat treatment of 150°C for 1hour will return the capacitance to its initial level.	If the parts are stored in a high temperature and humidity environment, problems such as reduced solderability caused by oxidation of terminal electrodes and deterioration of taping/packaging materials may take place. For this reason, components should be used within 6 months from the time of delivery. If exceeding the above period, please check solderability before using the capacitors.